

Search Notes

Application/Control No.

10/617,076

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

TANAKA, GENICHI

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	6	3/3/2006	JSL
716	7	3/3/2006	JSL
716	4	3/3/2006	JSL
716	5	3/3/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/3/2006	JSL
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/13/2006	JSL